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1 A 10-b 75-MSPS subranging A/D converter with integrated sample hold

Petschacher, R.; Zojer, B.; Astegher, B.; Jessner, H.; Lechner, A.;
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2 A 75 mW 10 b 20 MSample/s CMOS subranging ADC with 59 dB SNR

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